

DESCRIPTION

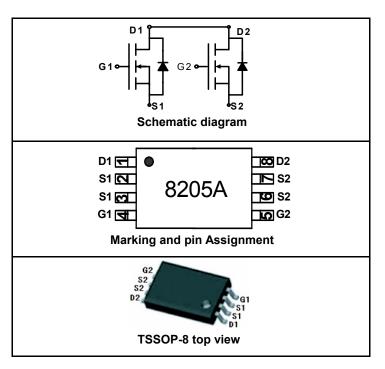
The SSF8205A uses advanced trench technology to provide excellent $R_{\rm DS(ON)},$ low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

GENERAL FEATURES

- $V_{DS} = 20V, I_D = 6A$ $R_{DS(ON)} < 37.5mΩ @ V_{GS} = 2.5V$ $R_{DS(ON)} < 27.5mΩ @ V_{GS} = 4.5V$
- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

Application

- Battery protection
- Load switch
- Power management



PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
8205A	SSF8205A	TSSOP-8	Ø330mm	12mm	3000 units

ABSOLUTE MAXIMUM RATINGS(TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	20	V
Gate-Source Voltage	V _G S	±10	V
Drain Current-Continuous@ Current-Pulsed (Note 1)	I _D	6	Α
Dialii Current-Continuous@ Current-ruiseu (Note 1)	I _{DM}	25	Α
Maximum Power Dissipation	P _D	1.5	W
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}\mathbb{C}$

THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	83	°C/W

ELECTRICAL CHARACTERISTICS (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS				_		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	20			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =18V,V _{GS} =0V			1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±10V,V _{DS} =0V			±100	nA
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	0.5	0.65	1.2	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =4.5A		21	27.5	mΩ
		V _{GS} =2.5V, I _D =3.5A		30	37.5	mΩ



SSF8205A

Forward Transconductance	g FS	V _{DS} =5V,I _D =4.5A	10		S
DYNAMIC CHARACTERISTICS (Note4)					
Input Capacitance	C _{lss}		600		PF
Output Capacitance	C _{oss}	V_{DS} =8 V , V_{GS} =0 V , F=1.0MHz	330		PF
Reverse Transfer Capacitance	C _{rss}	1 1.0141112	140		PF
SWITCHING CHARACTERISTICS (Note 4)					
Turn-on Delay Time	t _{d(on)}		10	20	nS
Turn-on Rise Time	t _r	V_{DD} =10V, I_{D} =1A V_{GS} =4.5V, R_{GEN} =6 Ω	11	25	nS
Turn-Off Delay Time	t _{d(off)}		35	70	nS
Turn-Off Fall Time	t _f		30	60	nS
Total Gate Charge	Qg		10	15	nC
Gate-Source Charge	Q_{gs}	$V_{DS}=10V,I_{D}=6A, V_{GS}=4.5V$	2.3		nC
Gate-Drain Charge	Q_{gd}	VGS 1.0V	3		nC
DRAIN-SOURCE DIODE CHARACTERISTICS					•
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =1.7A	0.72	1.2	V
Diode Forward Current (Note 2)	Is			1.7	Α

NOTES:

- **1.** Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
 4. Guaranteed by design, not subject to production testing.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

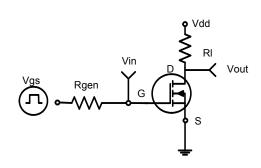


Figure 1:Switching Test Circuit

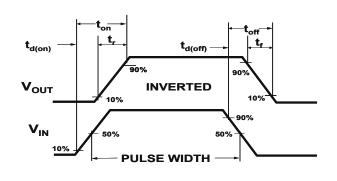


Figure 2:Switching Waveforms

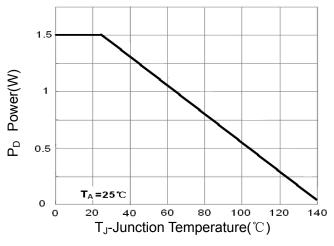


Figure 3 Power Dissipation

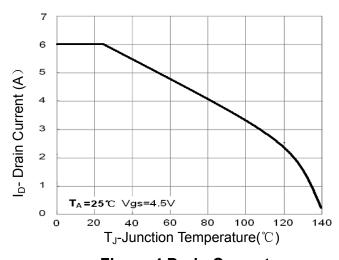


Figure 4 Drain Current

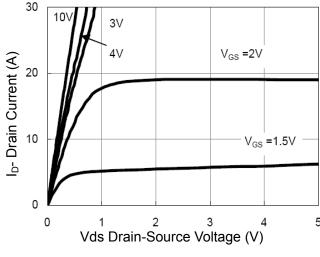


Figure 5 Output CHARACTERISTICS

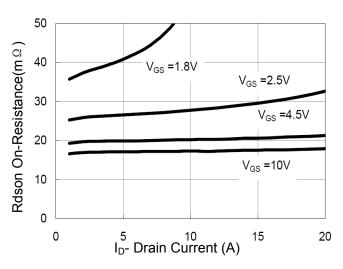


Figure 6 Drain-Source On-Resistance



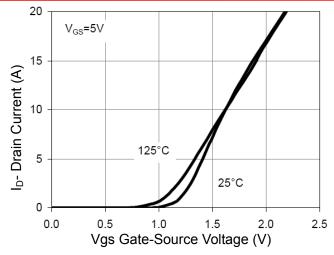


Figure 7 Transfer Characteristics

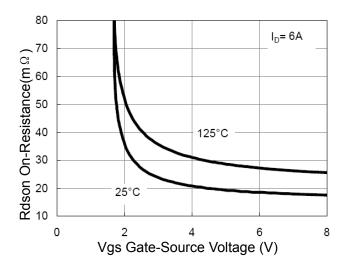


Figure 9 Rdson vs Vgs

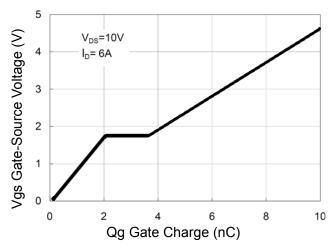


Figure 11 Gate Charge

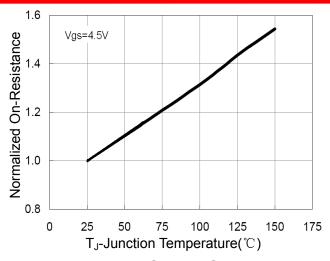


Figure 8 Drain-Source On-Resistance

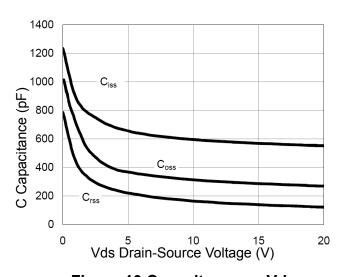


Figure 10 Capacitance vs Vds

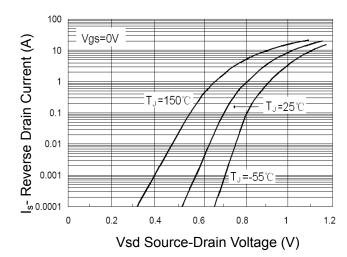


Figure 12 Source- Drain Diode Forward



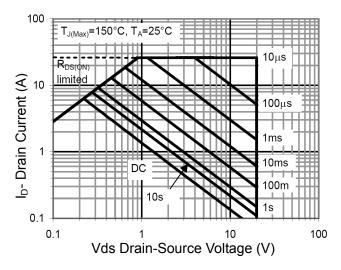


Figure 13 Safe Operation Area

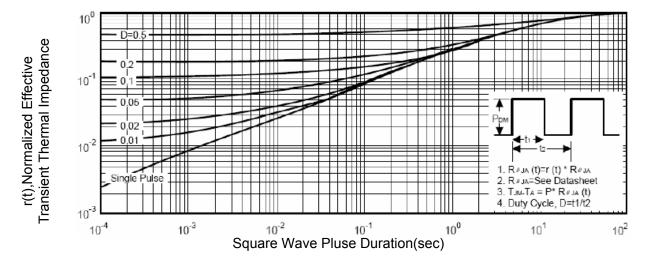
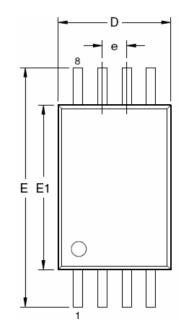


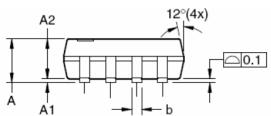
Figure 14 Normalized Maximum Transient Thermal Impedance

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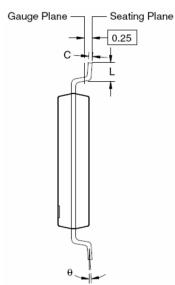


TSSOP-8 PACKAGE INFORMATION

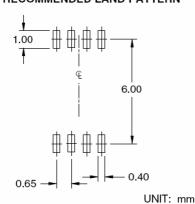




Dimensions in Millimeters (UNIT:mm) Gauge Plane -Seating Plane



RECOMMENDED LAND PATTERN



Dimensions in millimeters

Symbols	Min.	Nom.	Max.		
Α	_	_	1.20		
A1	0.05	_	0.15		
A2	0.80	1.00	1.05		
b	0.19	_	0.30		
С	0.09	_	0.20		
D	2.90	3.00	3.10		
E	6.40 BSC				
E1	4.30	4.40	4.50		
е	0.65 BSC				
L	0.45	0.60	0.75		
θ	0°	_	8°		

Dimensions in inches

Symbols	Min.	Nom.	Max.		
Α			0.047		
A1	0.002	_	0.006		
A2	0.031	0.039	0.041		
b	0.007	_	0.012		
С	0.004		0.008		
D	0.114	0.118	0.122		
Ε	0.252 BSC				
E1	0.169	0.173	0.177		
е	0.026 BSC				
L	0.018	0.024	0.030		
θ	0°	_	8°		

NOTES:

- 1. All dimensions are in millimeters.
- Dimensions are inclusive of plating
 Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 6 mils.
- 4. Dimension L is measured in gauge plane.
- 5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.



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